

## Abstract

### STOE DIFFRACTOMETERS – FOR SINGLE-CRYSTAL X-RAY DIFFRACTION

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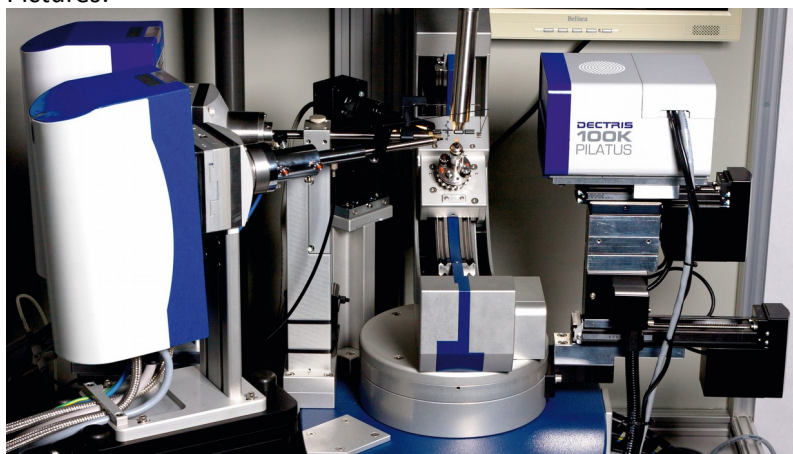
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Experimental factors such as crystal characteristics, available experiment time and the properties of X-ray sources and detectors have a strong impact on data quality and can make the difference between success and failure in phasing attempts, or they result in a more or less accurate atomic model. The talk focuses on the XRD equipment and is intended as an overview on recent developments of STOE X-ray diffraction systems.

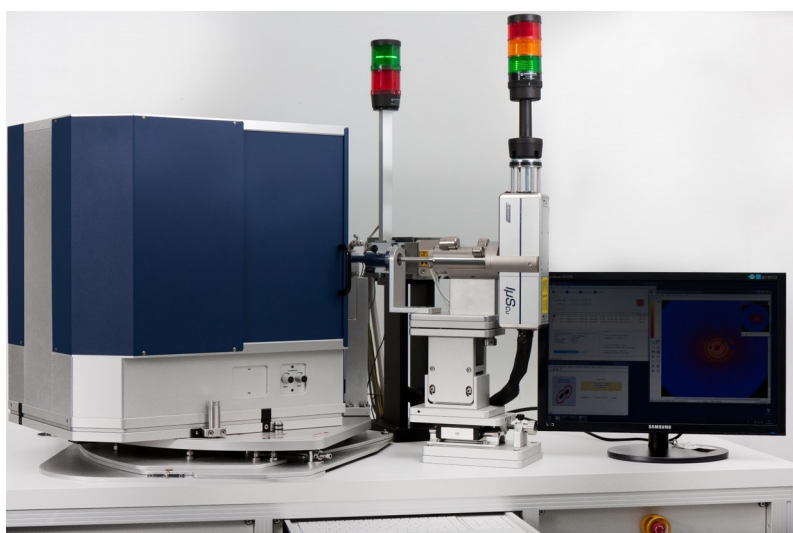
A variety of measurement setups with respect to goniometers, detectors and X-ray sources will be presented for Single-Crystal XRD applications. Additionally, recent advances in detector technology will be highlighted and the tangible benefits for the scientists will be made transparent, e.g. gaining measurement speed, improving data quality and acceptance of samples with complex crystallinity.

**Key words: STOE X-ray diffraction systems, novel detectors, data quality, data collection time.**

Pictures:



**Figure 1** Single-Crystal Diffractometer STADIVARI with micro-focus sources and hybrid pixel area detector



**Figure 2** Single-Crystal Diffractometer IPDS 2T with large image-plate detector and micro-focus source